PCN Number:	202	30328001.1 PCN Date:			March 30, 2023			
Title: Qualification of new			b site (FFAB) using o	ualified Pr	ocess	Techno	ology, Die Revision	
and additiona	al Ass	e mbl	y BOM options for se	elect devic	es			
<b>Customer Contact:</b>	<u> </u>	PCN M	<u>lanager</u>	Dept:			Quality Services	
Proposed 1 <sup>st</sup> Ship Date	: J	un 30	0, 2023	Sample r	-		April 30, 2023*	
*Sample requests rece	eived	afte	r April 30, 2023 w	ill not be	supp	orted.		
Change Type:								
☐ Assembly Site		$\square$	Assembly Process			Assen	nbly Materials	
☑ Design			Electrical Specifica	tion		Mecha	nical Specification	
☐ Test Site		$\square$	Packing/Shipping/L	abeling		Test P	rocess	
☐ Wafer Bump Site			Wafer Bump Mater	ial		Wafer Bump Process		
			Wafer Fab Materials		$\boxtimes$	Wafer	Fab Process	
			Part number change					
			PCN Detai	ls				

# **Description of Change:**

Texas Instruments is pleased to announce the qualification of a new fab & process technology (FFAB, BICOM3XHV) and assembly BOM options for selected devices as listed below in the product affected section.

С	urrent Fab Site	)	Additional Fab Site				
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter		
SFAB	JIBB	150 mm	FFAB	BICOM3XHV	200 mm		

The die was also changed as a result of the process change.

Assembly BOM options are noted below for both Group 1 and Group 2 device:

	Current	Additional
Bond wire composition, diameter	Au, 1.2	Cu,1.0 mil
Mold Compound	4209640	4226323
Mount Compound	4205846	4147858
Die coat step	TI Malaysia	Bump Site

For the devices in Group 2, they will also be subjected to the following changes in addition to above:

	Current	Additional
Die /Product Technology	Single die solution	Dual Die Solution
Bond	Single Bond (pins 4 & 11)	Double Bond (pins 4 & 11)

Qual details are provided in the Qual Data Section.

### **Reason for Change:**

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

#### **Impact on Environmental Ratings:**

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
☑ No Change	No Change	No Change	☑ No Change

# Changes to product identification resulting from this PCN:

#### **Fab Site Information:**

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
SH-BIP-1	SHE	USA	Sherman
FR-BIP-1	TID	DEU	Freising

#### Die Rev:

Current New

Die Rev [2P]	Die Rev [2P]
B, D	A

Sample product shipping label (not actual product label)



MSL 2 /260C/1 YEAR SEAL DT 03/29/04 OPT: ITEM: 5A (L)T0:1750



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (201) 660: SHE (211) CCO: USA (22L) ASO: MLA (23L) ACO: MYS

## **Product Affected:**

## **Group 1 Device list:**

OPA277UA	OPA277UA/2K5E4	OPA277UAE4	OPA277UAG4
OPA277UA/2K5			

#### **Group 2 Device list:**

0. 0 up = 201.00	· <del>-</del>		
OPA4277UA	OPA4277UA/2K5E4	OPA4277UAE4	OPA4277UAG4
OPA4277UA/2K5			

For alternate parts with similar or improved performance, please visit the product page on <a href="II.com">II.com</a>

#### Qualification Report Approve Date 15-March-2023

#### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: <u>OPA277UA</u>	QBS Process Reference: <u>INA849DR</u>	QBS Package Reference: <u>INA821ID</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0
HAST	A2	Temperature Humidity Bias	85C/85%RH	1000 Hours	-	3/231/0	-
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	3/231/0
HTOL	B1	Life Test	100C <sup>A</sup>	300 Hours	-	1/77/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	3/231/0
ESD	E2	ESD CDM	-	500 Volts	1/3/0	-	-
ESD	E2	ESD CDM	-	750 Volts	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	1500 Volts	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/3/0	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	3/90/0

- QBS: Qual By Similarity
- Qual Device OPA277UA is qualified at MSL2 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47:-55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

# Qualification Report Approve Date 14-NOVEMBER -2022

**Qualification Results** 

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: OPA4277UA	QBS Process Reference: OPA202ID	QBS Process Reference: INA828ID	QBS Process Reference: INA821ID	QBS Process Reference: OPA207ID	QBS Package Reference: QPA4187ID	QBS Package Reference: OPA4227UA	QBS Pacage Reference: OPA4388ID	QBS Product Reference: <u>OPA2277U</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	-	2/154/0	-
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	2/154/0	-
тс	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	2/154/0	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/231/0	3/231/0	-	-	-	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0	3/231/0	3/231/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	3/231/0	-	-	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	3/231/0	3/231/0	-	-	-	-
ESD	E2	ESD CDM		1000 Volts	-	-	-	-	-	-	1/3/0	-	1/3/0
ESD	E2	ESD CDM	-	1750 Volts	-	-	-	-	-	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	1/3/0	-	1/3/0	1/3/0	1/3/0	1/3/0	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	1/3/0	1/3/0	1/3/0	-	1/3/0

	LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	1/6/0	1/6/0	1/3/0	1/6/0	1/3/0	1/3/0	1/3/0
C	HAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	3/90/0	3/90/0	3/90/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0

- · QBS: Qual By Similarity
- Qual Device OPA4277UA is qualified at MSL2 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
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- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47:-55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at Ti's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	PCN ww admin team@list.ti.com

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